

**Search Notes**

Application/Control No.

10/661,624

Examiner

BINH K. TIEU

Applicant(s)/Patent under  
Reexamination

BROK ET AL.

Art Unit

2643

**SEARCHED**

Class	Subclass	Date	Examiner
4555	433	1/6/2006	BKT
	414.1		
	414.3		
	422.1		
	426.1		
	428		
	432.1		
	432.3		
	435.1		
	435.2		
	435.3		
↓	436, 448	↓	↓

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner